### STS8C5H30L



# N-channel 30 V, 0.018 Ω typ., 8 A, P-channel 30 V, 0.045 Ω typ., 5 A Power MOSFET in a SO-8 package

Datasheet - production data

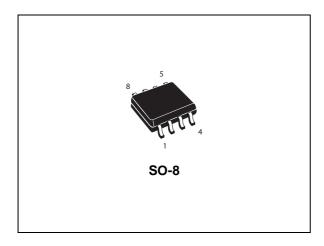
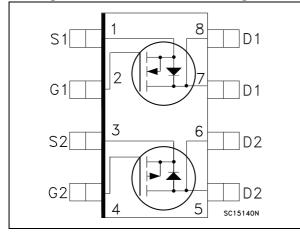


Figure 1. Internal schematic diagram



#### **Features**

Order code	Channel	V <sub>DS</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
STS8C5H30L	N	30 V	0.022 Ω	8 A
3136C5H30L	Р	30 V	$0.055~\Omega$	5 A

- Conduction losses reduced
- Switching losses reduced
- · Low threshold drive
- Standard outline for easy automated surface mount assembly

### **Applications**

· Switching applications

### **Description**

This device is a complementary N-channel and P-channel Power MOSFET developed using STripFET™ II (P-channel) and STripFET™ V (N-channel) technologies. The resulting transistors show extremely high packing density for low onresistance and rugged avalanche characteristics.

**Table 1. Device summary** 

Order code	Marking	Packages	Packaging
STS8C5H30L	8C5H30L	SO-8	Tape and reel

Contents STS8C5H30L

### **Contents**

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STS8C5H30L Electrical ratings

# 1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Val	Unit	
Symbol	Farameter	N-channel	P-channel	Offic
V <sub>DS</sub>	Drain-source voltage	30	)	V
V <sub>GS</sub>	Gate- source voltage	±16	±16	V
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 25°C single operating	8	5.4	Α
I <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 100°C single operating	6.4	4.3	Α
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	32	21.6	Α
В	Total dissipation at T <sub>C</sub> = 25°C dual operating	1.6		W
P <sub>TOT</sub>	Total dissipation at $T_C = 25^{\circ}C$ single operating 2		W	
T <sub>stg</sub>	Storage temperature	-55 to 150		°C
T <sub>j</sub>	Operating junction temperature	15	0	°C

<sup>1.</sup> Pulse width limited by safe operating area

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-a</sub> (1)	Thermal resistance junction-ambient single operating	62.5	°C/W
R <sub>thj-a</sub> (1)	Thermal resistance junction-ambient dual operating	78	°C/W

<sup>1.</sup> When mounted on 1 inch<sup>2</sup> FR-4 board, 2 oz. Cu.,  $t \le 10$  sec

Note: For the p-channel MOSFET actual polarity of voltages and current has to be reversed

### 2 Electrical characteristics

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(T<sub>CASE</sub> = 25 °C unless otherwise specified)

Table 4. On/off states

Symbol	Parameter	Test conditions	Channel	Min.	Тур.	Max.	Unit
V	Drain-source	V = 0 L = 250 4/A	N	30			V
V <sub>(BR)DSS</sub>	breakdown voltage	$V_{GS} = 0, I_D = 250 \mu\text{A}$	Р	30			٧
	Zero gate voltage	$V_{GS} = 0, V_{DS} = 30 \text{ V}$	N			1	μΑ
I <sub>DSS</sub>		$V_{GS} = 0$ , $V_{DS} = 30$ V, $T_{C} = 125$ °C	Р			10	μΑ
	Gate-body leakage	$V_{DS} = 0, V_{GS} = \pm 16 \text{ V}$	N			±100	nA
GSS	I <sub>GSS</sub> current	$V_{DS} = 0$ , $V_{GS} = \pm 16 \text{ V}$	Р			±100	nA
V	Gate threshold voltage	V V - 1 - 250 uA	N	1	1.6	2.5	٧
V <sub>GS(th)</sub>	Gate illieshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	Р	1	1.6	2.5	V
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4 A	N		0.018	0.022	Ω
D .	Static drain-source	$V_{GS} = 10 \text{ V}, I_D = 2.5 \text{ A}$	Р		0.045	0.055	Ω
R <sub>DS(on)</sub>	on-resistance	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 4 A	N		0.020	0.025	Ω
		$V_{GS} = 4.5 \text{ V}, I_D = 2.5 \text{ A}$	Р		0.070	0.075	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Channel	Min.	Тур.	Max.	Unit
g <sub>fs</sub> <sup>(1)</sup>	Forward	$V_{DS} = 15 \text{ V}, I_{D} = 4 \text{ A}$	N	-	8.5		S
9fs ` ′	transconductance	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 2.5 A	Р	-	10		S
C	Input capacitance		N	1	857		pF
C <sub>iss</sub>	input capacitance		Р	-	1350		pF
	Output capacitance	V <sub>GS</sub> = 0, V <sub>DS</sub> = 25 V, f = 1 MHz	N	-	147		pF
C <sub>oss</sub>	oss Output capacitance		Р	-	490		pF
_	Reverse transfer		N	-	20		pF
C <sub>rss</sub>	capacitance		Р	-	130		pF
	Total gate charge	N-channel	N	-	7	10	nC
Qg	Total gate charge	Fotal gate charge N-channel V <sub>DD</sub> =24 V I <sub>D</sub> =8 A	Р	-	12.5	16	nC
	Cata source charge	V <sub>GS</sub> =5 V P-channel V <sub>DD</sub> = 24 V I <sub>D</sub> = 4 A	N	-	2.5		nC
Q <sub>gs</sub>	Gate-source charge		Р	-	5		nC
	Gate-drain charge	V <sub>GS</sub> = 5 V	N	-	2.3		nC
Q <sub>gd</sub> Ga		(see Figure 27)	Р	-	3		nC

<sup>1.</sup> Pulsed: Pulse duration = 300  $\mu$ s, duty cycle 1.5.

For the p-channel MOSFET actual polarity of voltages and current has to be reversed

Table 6. Switching times

Symbol	Parameter	Test conditions	Channel	Min.	Тур.	Max.	Unit
+	Turn on dolay time		N	-	12	-	ns
<sup>t</sup> d(on)	t <sub>d(on)</sub>   Turn-on delay time	n) Turn-on delay time N-channel	Р	-	25	-	ns
	Rise time	V <sub>DD</sub> = 15 V, I <sub>D</sub> = 4 A	N	-	14.5	-	ns
ι <sub>r</sub>	t <sub>r</sub> Rise time	$R_G$ =4.7 Ω, $V_{GS}$ = 4.5 V P-channel	Р	-	35	-	ns
+	t <sub>d(off)</sub> Turn-off delay time	V <sub>DD</sub> = 15 V, I <sub>D</sub> = 2 A	N	-	23	-	ns
<sup>L</sup> d(off)		$R_{G}$ =4.7 $\Omega$ , $V_{GS}$ = 4.5 $V$	Р	-	125	-	ns
	t <sub>f</sub> Fall time	Figure 26	N	-	8	-	ns
τ <sub>f</sub>			Р	-	35	-	ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Channel	Min.	Тур.	Max.	Unit
1.	Source-drain current		N	-		8	Α
I <sub>SD</sub>	Source-drain current		Р	-		5	Α
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current		N	-		32	Α
'SDM`	(pulsed)		Р	-		20	Α
V (2)	V <sub>SD</sub> <sup>(2)</sup> Forward on voltage	I <sub>SD</sub> = 8 A, V <sub>GS</sub> = 0	N	-		1.5	٧
V <sub>SD</sub> ` ′		I <sub>SD</sub> = 5 A, V <sub>GS</sub> = 0	Р	-		1.2	٧
+	Reverse recovery	N-channel	N	-	15		ns
t <sub>rr</sub>	time	$I_{SD} = 8 \text{ A, di/dt} = 100 \text{ A/}\mu\text{s}$	Р	-	45		ns
	Reverse recovery	V <sub>DD</sub> =15 V,T <sub>j</sub> =150 °C P-channel	N	-	5.7		nC
Q <sub>rr</sub>	charge	I <sub>SD</sub> = 5 A, di/dt = 100 A/μs	Р	-	36		nC
	Reverse recovery current	V <sub>DD</sub> =15 V, T <sub>j</sub> =150 °C	N	-	0.76		Α
IRRM		Figure 28	Р	-	1.6		Α

<sup>1.</sup> Pulse width limited by safe operating area.

Note: For the p-channel MOSFET actual polarity of voltages and current has to be reversed

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<sup>2.</sup> Pulsed: Pulse duration = 300  $\mu$ s, duty cycle 1.5%

#### **Electrical characteristics (curves)** 2.1

Figure 2. Safe operating area n-ch

AM03310v1 ΙD (A) 100 10 1ms 10ms 100ms Tj=150°C 1s Tc=25°C Sinlge pulse

Figure 3. Thermal impedance n-ch

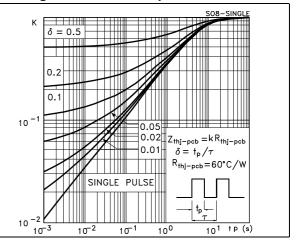
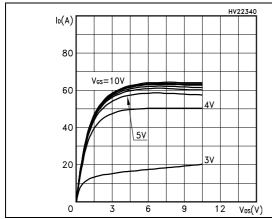


Figure 4. Output characteristics n-ch

Figure 5. Transfer characteristics n-ch



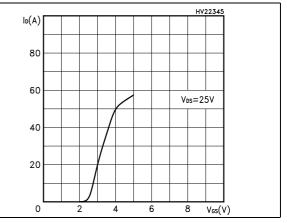
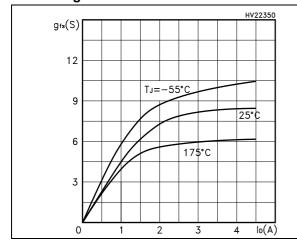


Figure 6. Transconductance n-ch

Figure 7. Static drain-source on resistance n-ch



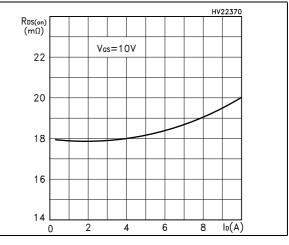
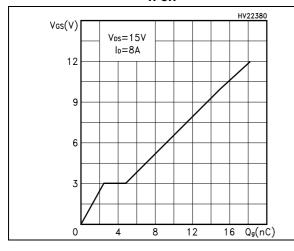


Figure 8. Gate charge vs. gate-source voltage n-ch

Figure 9. Capacitance variations n-ch



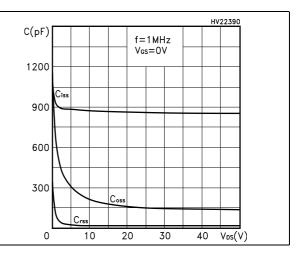
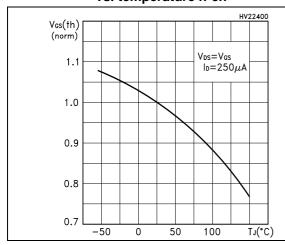


Figure 10. Normalized gate threshold voltage vs. temperature n-ch

Figure 11. Normalized on resistance vs. temperature n-ch



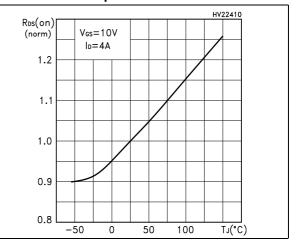
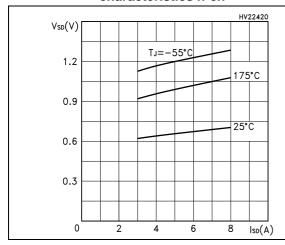
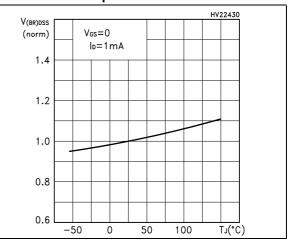


Figure 12. Source-drain diode forward characteristics n-ch

Figure 13. Normalized breakdown voltage vs. temperature n-ch





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Figure 14. Safe operating area p-ch

Figure 15. Thermal impedance p-ch

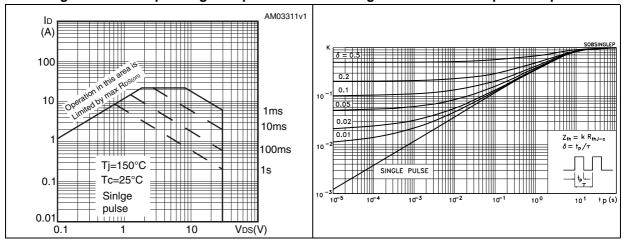


Figure 16. Output characteristics p-ch

Figure 17. Transfer characteristics p-ch

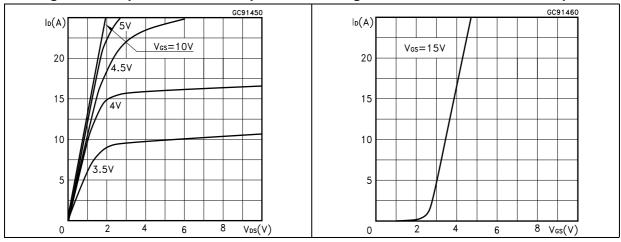


Figure 18. Transconductance p-ch

Figure 19. Static drain-source on resistance p-ch

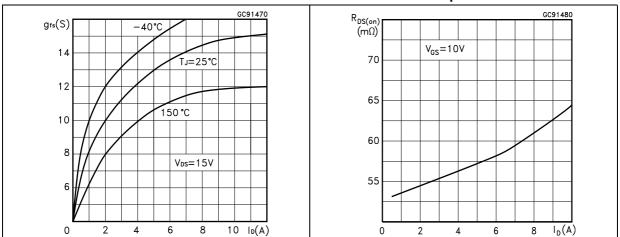
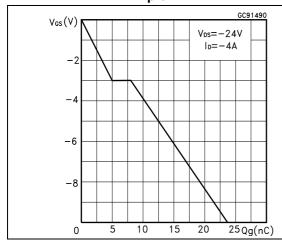


Figure 20. Gate charge vs. gate-source voltage p-ch

Figure 21. Capacitance variations p-ch



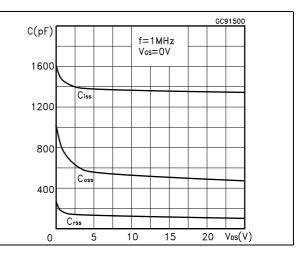
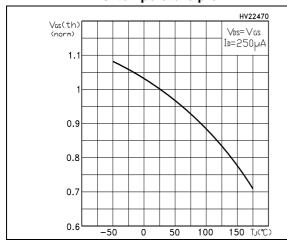


Figure 22. Normalized gate threshold voltage vs. temperature p-ch

Figure 23. Normalized on resistance vs. temperature p-ch



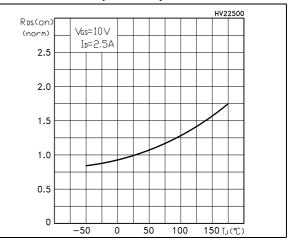
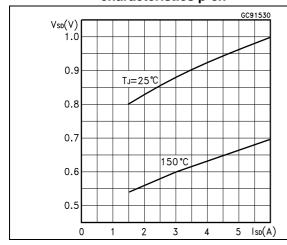
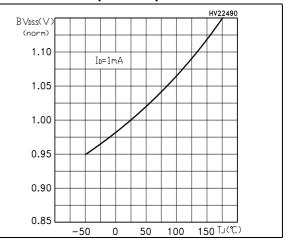


Figure 24. Source-drain diode forward characteristics p-ch

Figure 25. Normalized breakdown voltage vs. temperature p-ch





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STS8C5H30L Test circuits

### 3 Test circuits

Figure 26. Switching times test circuit for resistive load

Figure 27. Gate charge test circuit

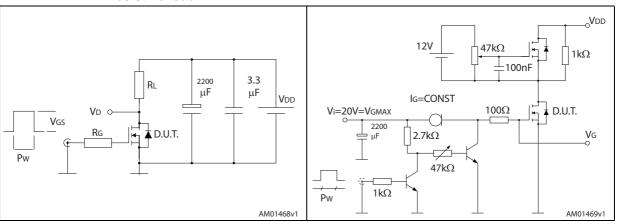


Figure 28. Test circuit for inductive load switching and diode recovery times

Figure 29. Unclamped inductive load test circuit

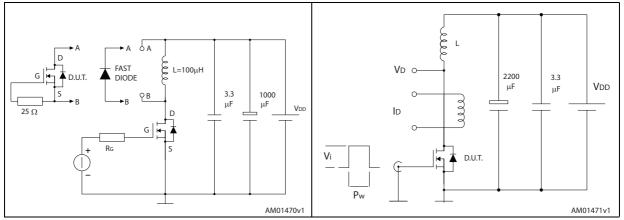
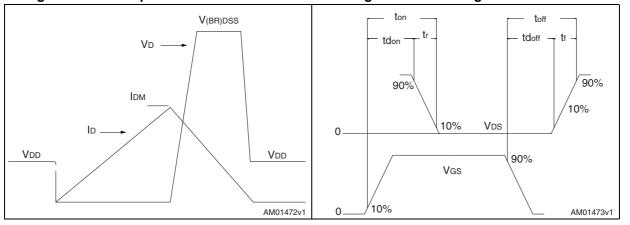


Figure 30. Unclamped inductive waveform

Figure 31. Switching time waveform



## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: <a href="https://www.st.com">www.st.com</a>. ECOPACK<sup>®</sup> is an ST trademark.

SEATING PLANE

SECTION B-B

SECTION B-B

O016023\_G\_FU

Figure 32. SO-8 drawing

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Table 8. SO-8 mechanical data

		mm	
Dim.	Min.	Тур.	Max.
А			1.75
A1	0.10		0.25
A2	1.25		
b	0.31		0.51
b1	0.28		0.48
С	0.10		0.25
c1	0.10		0.23
D	4.80	4.90	5.00
E	5.80	6.00	6.20
E1	3.80	3.90	4.00
е		1.27	
h	0.25		0.50
L	0.40		1.27
L1		1.04	
L2		0.25	
k	0°		8°
ccc			0.10



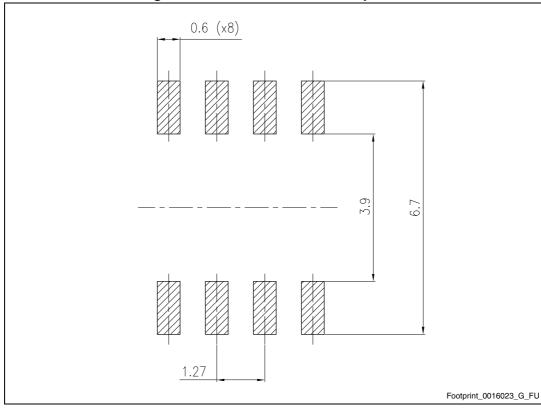


Figure 33. SO-8 recommended footprint<sup>(a)</sup>

a. All dimensions are in millimeters.

# 5 Packaging mechanical data

A Po Note: Drawing not in scale

Figure 34. SO-8 tape and reel dimensions

Table 9. SO-8 tape and reel mechanical data

Dim.		mm	
Dilli.	Min.	Тур.	Max.
Α		-	330
С	12.8	-	13.2
D	20.2	-	
N	60	-	
Т		-	22.4
Ao	8.1	-	8.5
Во	5.5	-	5.9
Ko	2.1	-	2.3
Po	3.9	-	4.1
Р	7.9	-	8.1

STS8C5H30L Revision history

# 6 Revision history

Table 10. Revision history

Date	Revision	Changes
17-Sep-2004	1	First revision.
31-Oct-2006	2	The document has been reformatted.
30-Jan-2007	3	typo mistake on <i>Table 2</i> .
23-Jul-2007	4	Figure 14 has been updated.
23-Feb-2009	5	Figure 2, Figure 3, Figure 14 and Figure 15 have been changed.
10-Jun-2010	6	Updated V <sub>GS(th)</sub> in <i>Table 4: On/off states</i> .
13-Jun-2014	7	<ul> <li>Modified: title</li> <li>Modified: Description</li> <li>Modified: marking in Table 1</li> <li>Updated: Section 4: Package mechanical data</li> <li>Minor text changes</li> </ul>

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